

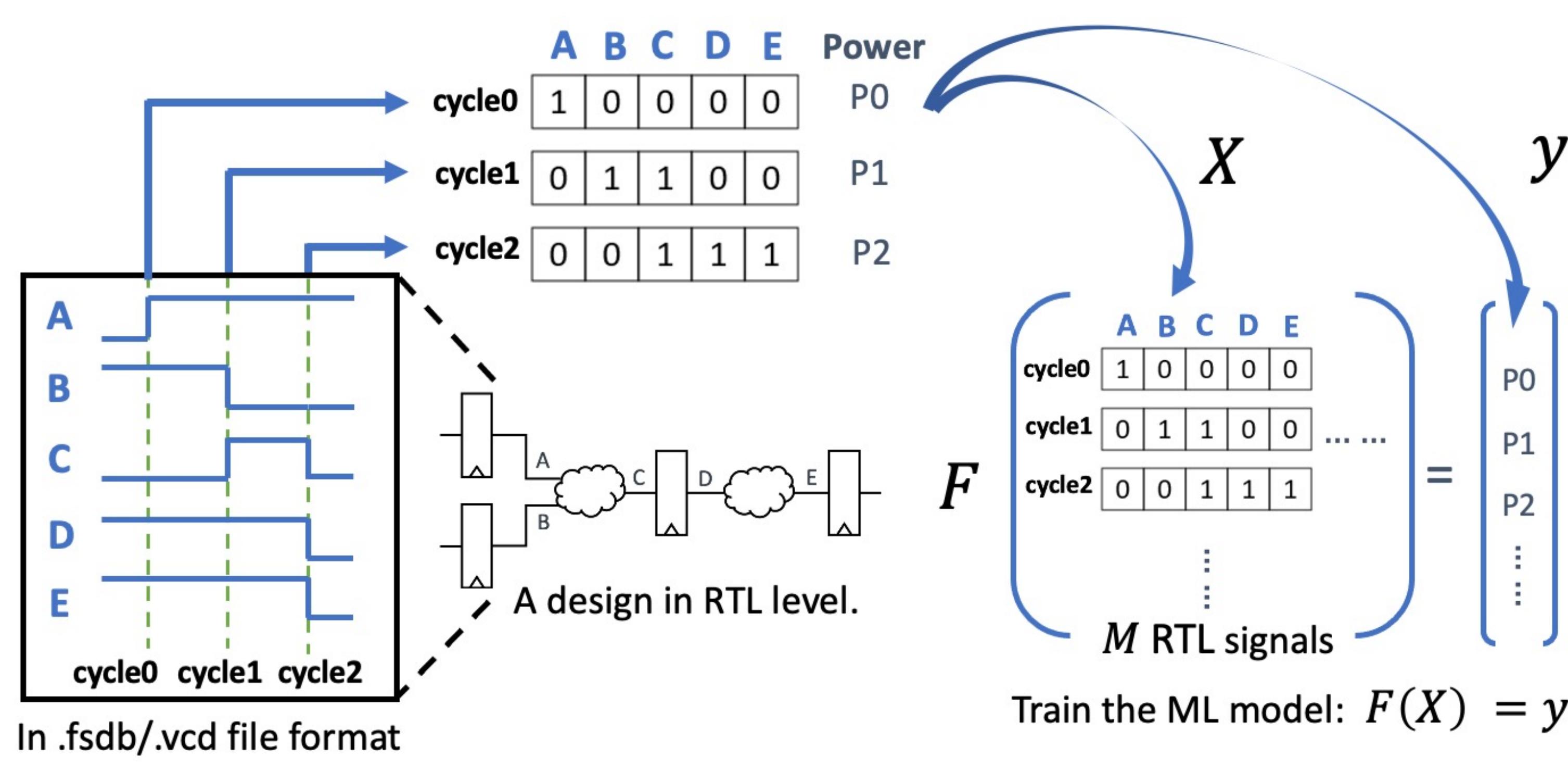
DEEP: Developing Extremely Efficient Runtime On-Chip Power Meters

Zhiyao Xie¹, Shiyu Li², Mingyuan Ma², Chen-Chia Chang²,
Jingyu Pan², Yiran Chen², Jiang Hu³

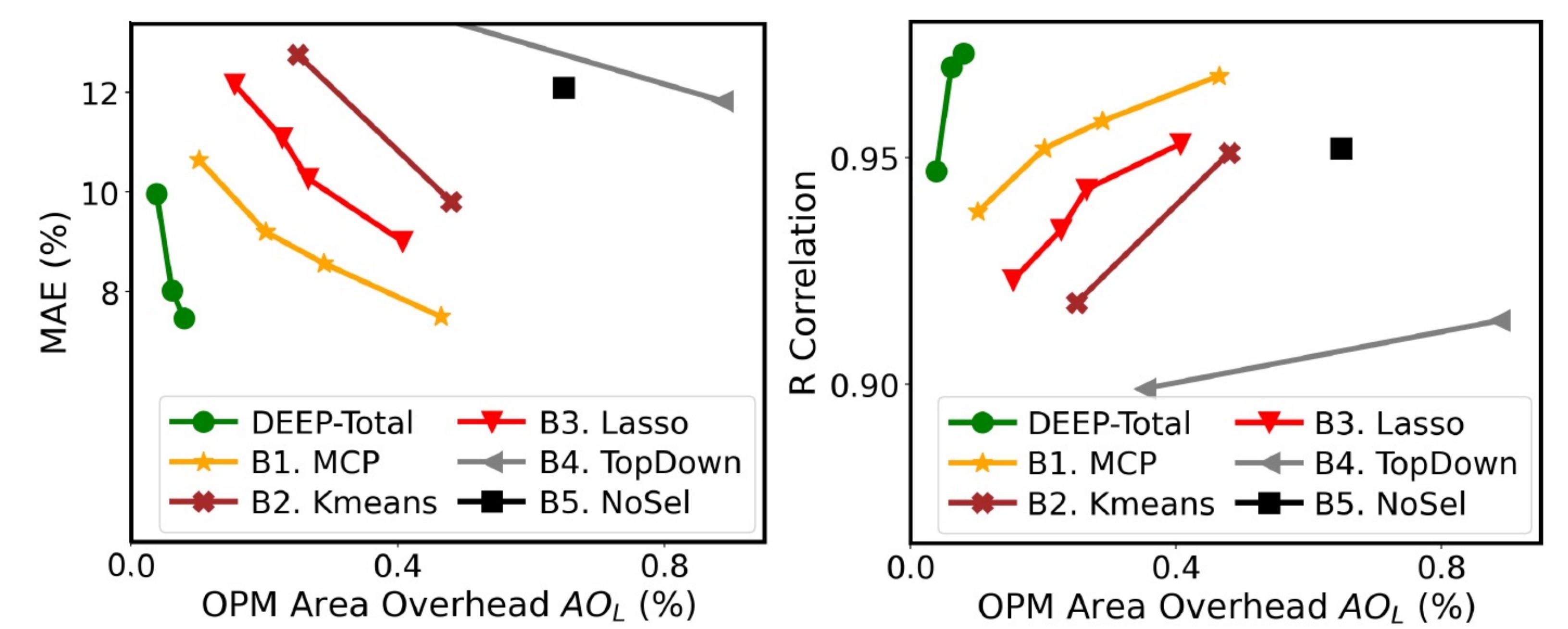
¹Hong Kong University of Science and Technology, ²Duke University, ³Texas A&M University

INTRODUCTION

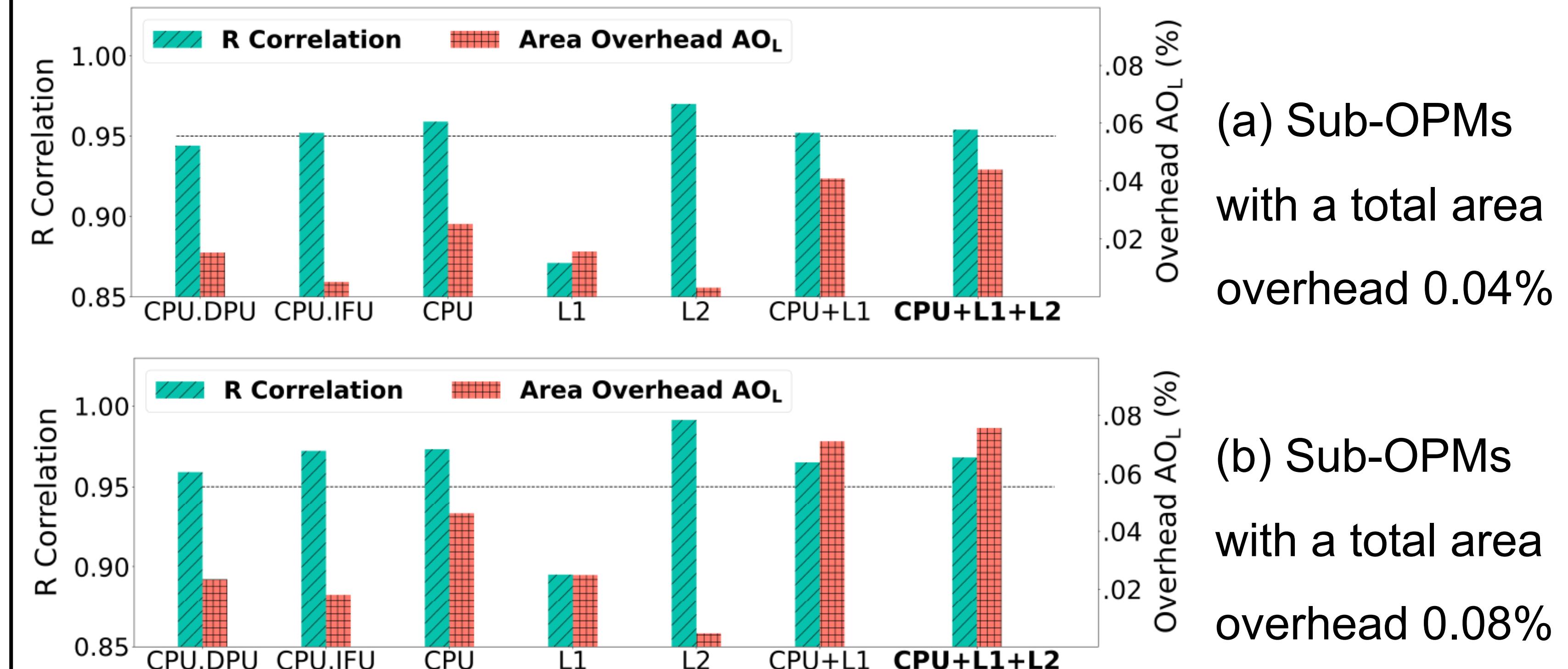
Baseline Methods	Model Input Candidate V_M (Candidate Count M)	Temporal Resolution	Claimed OPM Area Overhead
B1. MICRO'21 [38]	All RTL signals (178 K)	Per-cycle	< 1%
B2. MICRO'19 [20]	All RTL signals (178 K)	100s cycles	N/A
B3. DATE'18 [25]	Registers (67 K)	> 1K cycles	7%
B4. DATE'18 [41]	Module I/O signals (< 178K)	100s cycles	4 – 10%
B5. ASPDAC'15 [39]	Registers (67 K)	Per-cycle	16%
DEEP (this work)	All bits of RTL signals (578 K)	Per-cycle	< 0.1%



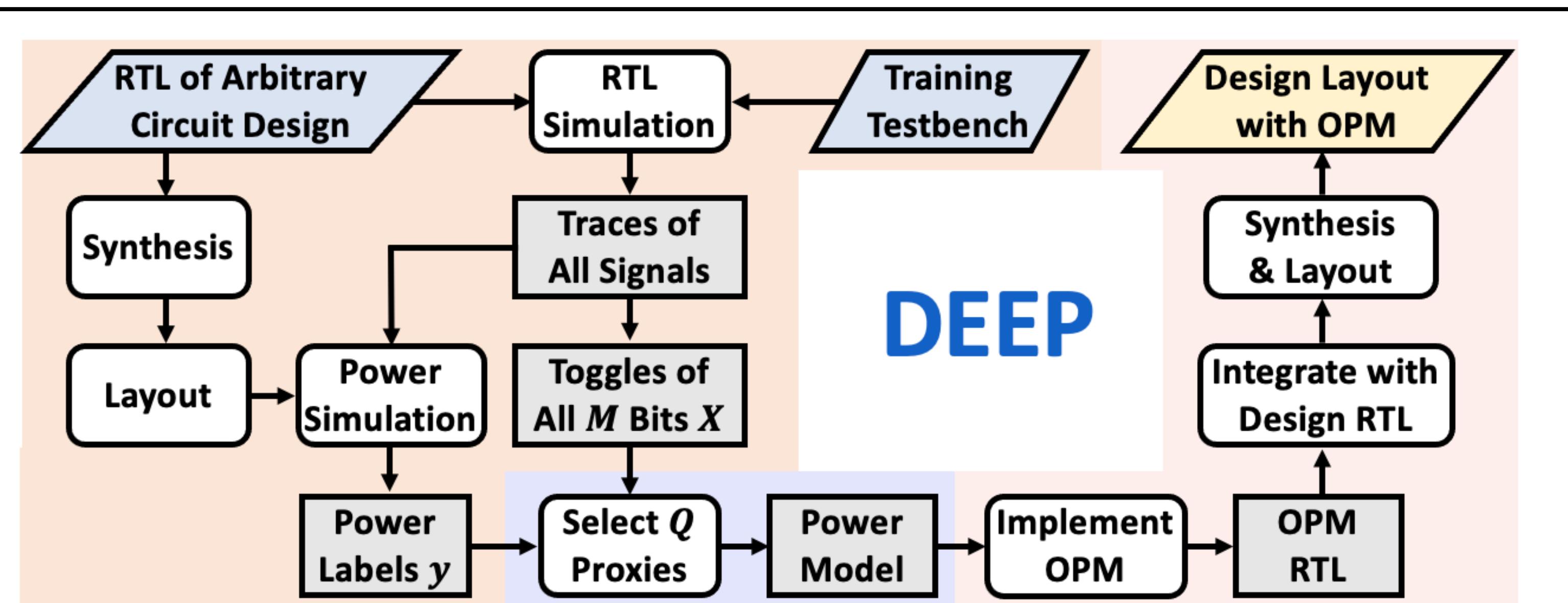
EVALUATION & RESULTS



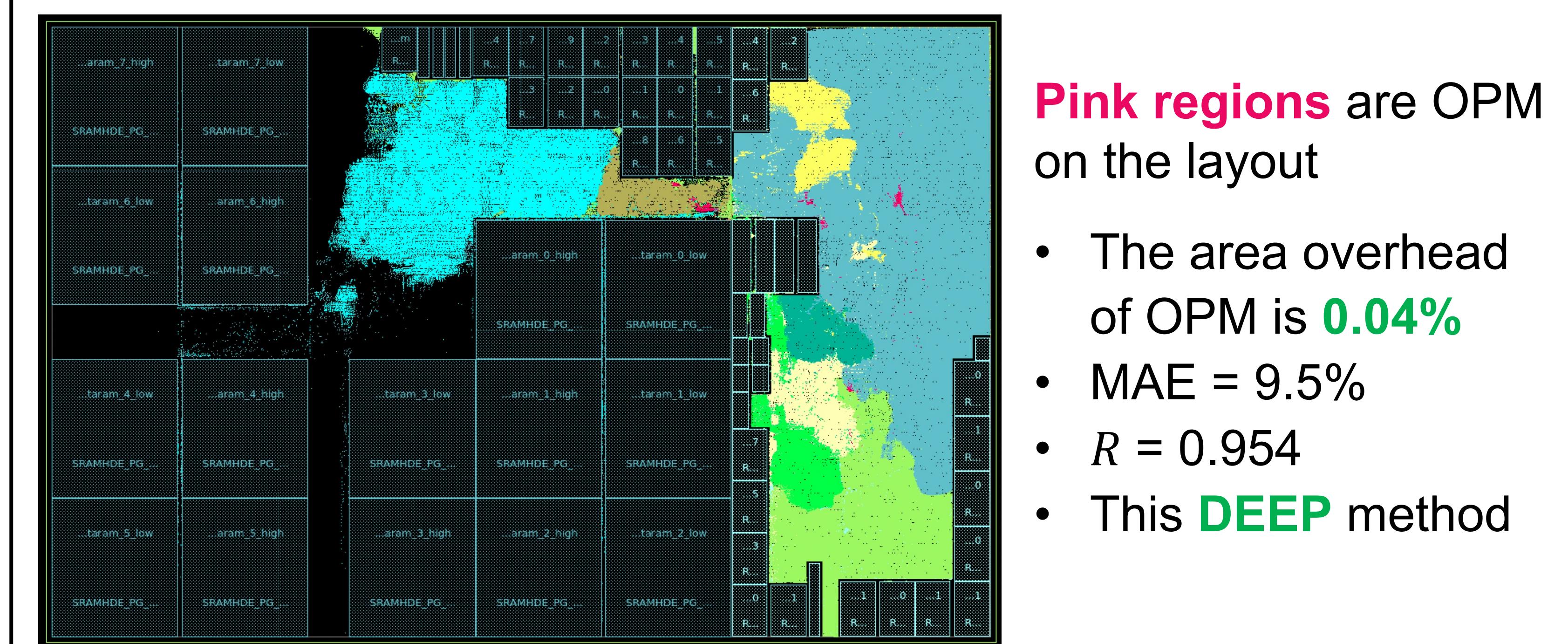
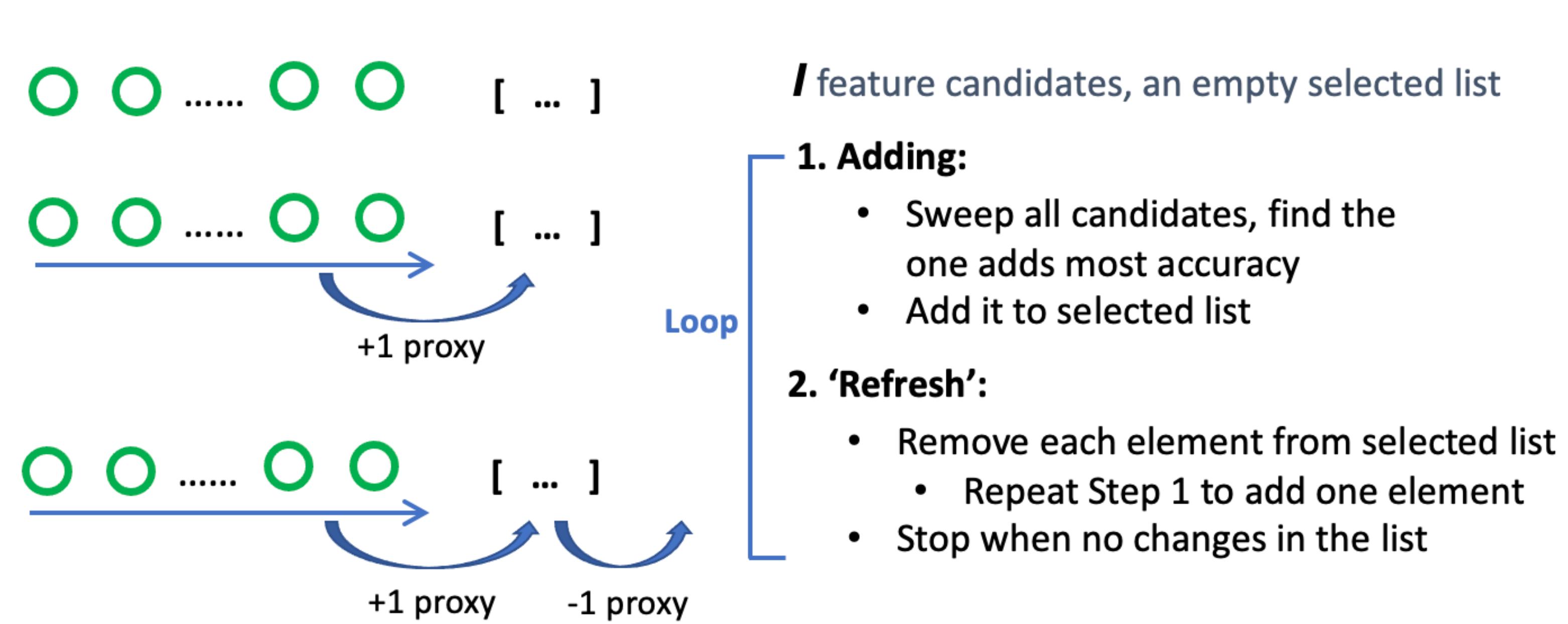
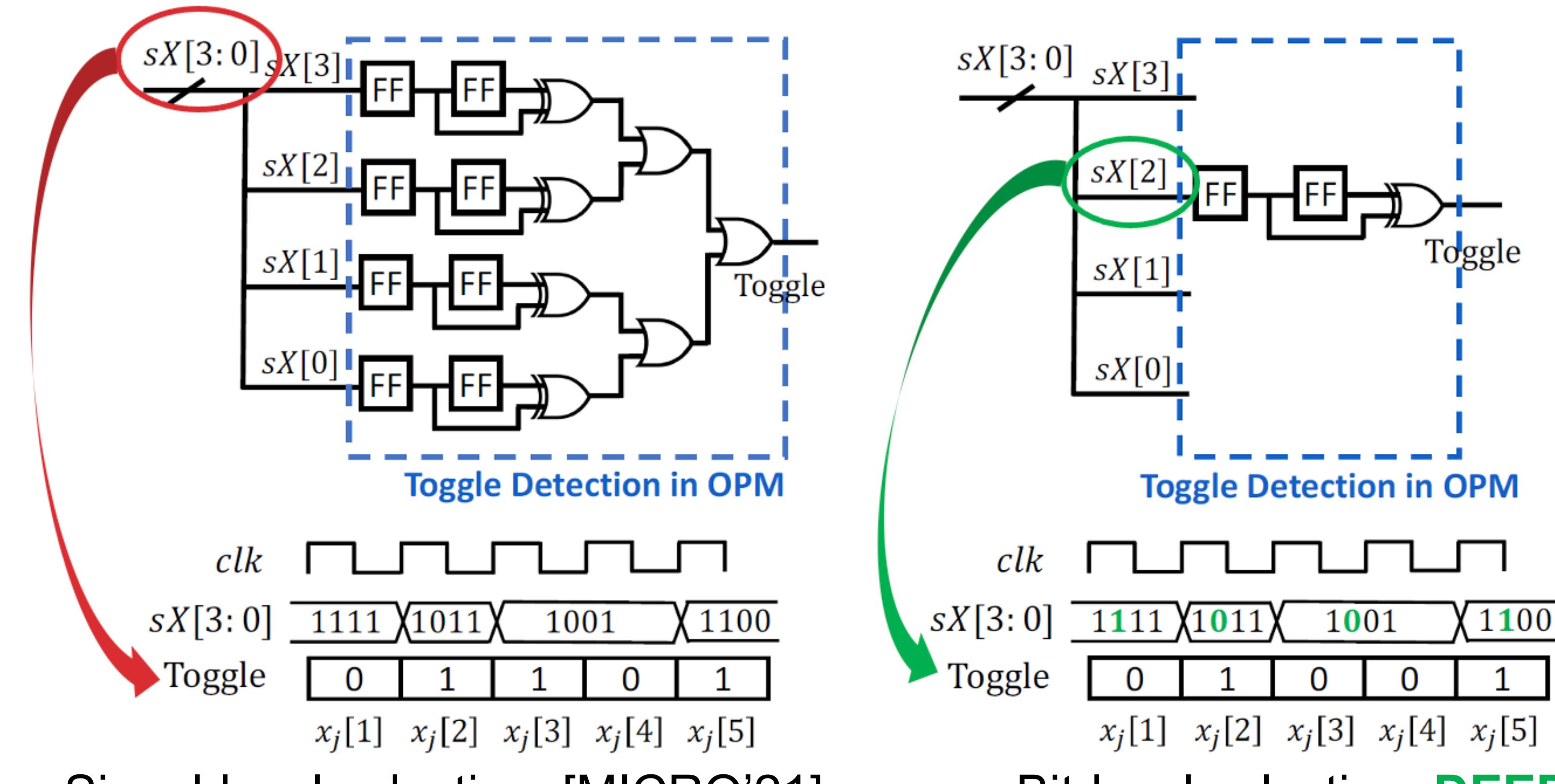
OPM hardware cost vs. per-cycle power prediction accuracy.



METHODOLOGY

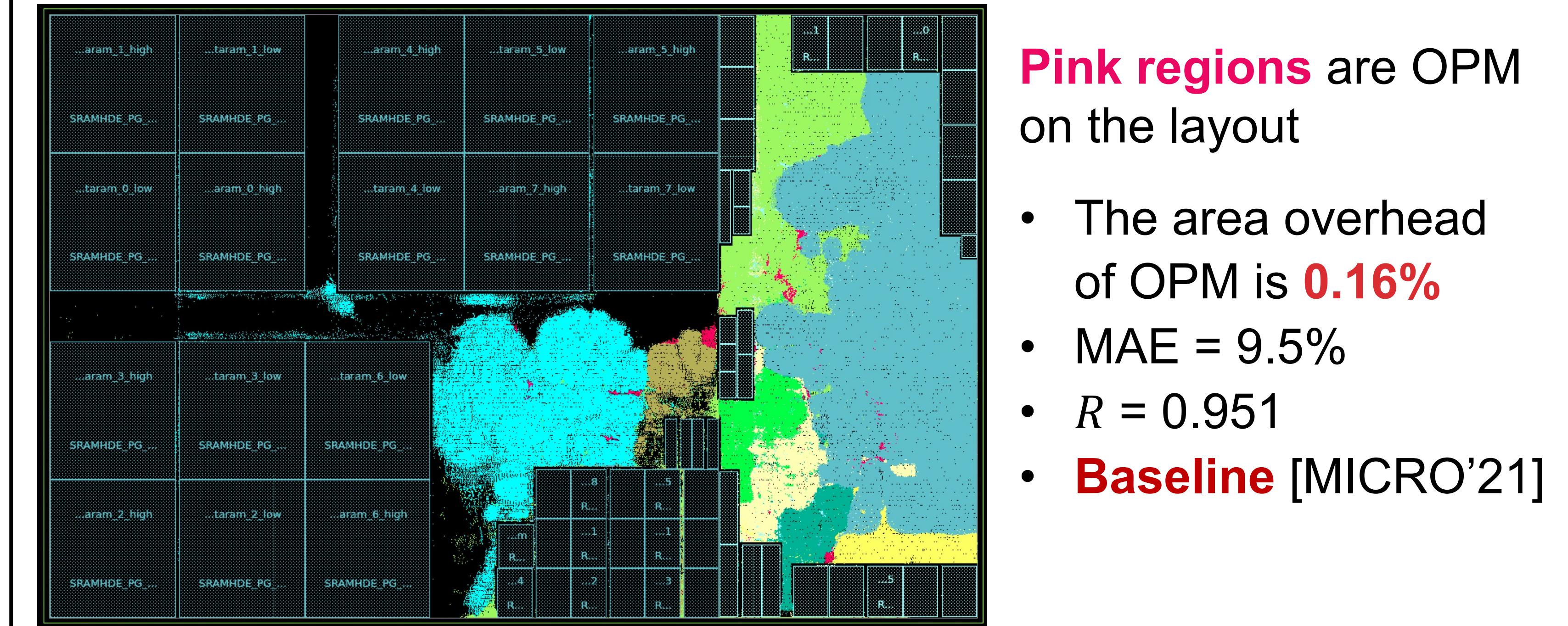


1. Generate data with **waveform of signals** and **power labels**
2. Develop OPM by selecting minimum signals as input
3. Implement the OPM as part of circuit design



Pink regions are OPM on the layout

- The area overhead of OPM is 0.04%
- MAE = 9.5%
- R = 0.954
- This DEEP method



Pink regions are OPM on the layout

- The area overhead of OPM is 0.16%
- MAE = 9.5%
- R = 0.951
- Baseline [MICRO'21]

